



Report No .:

EMC 1809095

File reference No.:

2018-09-19

Applicant:

Product:

Charging Cable

Brand Name:

N/A

Model No .:

MC18

Test Standards:

EN 55032:2015

EN61000-3-2:2014

EN 55024: 2010+A1:2015

EN 61000-3-3: 2013

Test result:

The EMC testing has been performed on the submitted samples and found in compliance with council EMC Directive

samples and found in compliance with council Ewic Directiv

2014/30/EU.

Approved By

Terry Tang Manager

Dated:

September 19, 2018

Results appearing herein relate only to the sample tested

The technical reports is issued errors and omissions exempt and is subject to withdrawal at

## SHENZHEN TIMEWAY TESTING LABORATORIES.

Zone C, 1st Floor, Block B, Jun Xiang Da Building, Zhongshan Park Road West, Tong Le Village, Nanshan District, Shenzhen, China

Tel (755) 83448688

Fax (755) 83442996

Email: info@timeway-lab.com

Date: 2018-09-19



# **Special Statement:**

The testing quality ability of our laboratory meet with "Quality Law of People's Republic of China" Clause 19.

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The testing quality system of our laboratory meets with ISO/IEC-17025 requirements, which is approved by CNAS. This approval result is accepted by MRA of APLAC.

Our test facility is recognized, certified, or accredited by the following organizations:

#### **CNAS-LAB Code: L2292**

The EMC Laboratory has been assessed and in compliance with CNAS-CL01 accreditation criteria for testing Laboratories (identical to ISO/IEC 17025:2005 General Requirements) for the Competence of testing Laboratories.

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#### 1.0 General Details

#### 1.1 Test Lab Details

SHENZHEN TIMEWAY TESTING LABORATORIES.

Zone C, 1st Floor, Block B, Jun Xiang Da Building, Zhongshan Park Road West, Tong Le Village, Nanshan District, Shenzhen, China

Tel(086) 755-83448688 Fax (086) 755-83442996

#### **Test Location**

#### All tests were performed at:

SHENZHEN TIMEWAY TESTING LABORATORIES.

Zone C, 1st Floor, Block B, Jun Xiang Da Building, Zhongshan Park Road West, Tong Le Village, Nanshan District, Shenzhen, China

Tel(086) 755-83448688 Fax (086) 755-83442996

No tests were sub-contracted.

## 1.2 Applicant Details

Applicant:

Address:

Telephone:

Fax:

Manufacturer:

Address:

Telephone: --

Fax:

#### 1.3 Description of EUT

Product: Charging Cable

Brand Name: N/A
Model Number: MC18
Adding Model Number: N/A

Rating: Input: --

Remark: --

## 1.4 Submitted Sample(s)

1 Sample

#### 1.5 Test Duration

Date of Receipt of Test Item: September 18, 2018

Date of Test: September 18, 2018~ September 19, 2018

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#### Additional information of EUT

	Submitted	Not Available
User Manual		
Part List		
Circuit Diagram		
Printed circuit board[PCB] Layout		
Block Diagram		
1.7 Test Engineer	ATESTING L	BOR
The sample(s) tested by Print	Name: Leo Lau/Engin	eer

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## 2.0 List of Measurement Equipment

#### 2.1 Conducted Emission Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESH3	860905/006	RS	2018.06.11	1Year
Spectrum Analyzer	ESA-L1500A	US37451154	HP	2018.06.11	1Year
PULSE LIMITER	ESH3-Z2	100281	RS	2018.06.11	1Year
LISN	ESH3-Z5	100294	RS	2018.06.11	1Year
LISN	ESH3-Z5	100253	RS	2018.06.11	1Year

#### 2.2 Radiated Disturbance Test

				Calibration	Calibration
Name	Model No	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESVD	100008	RS	2018.06.11	1Year
Coaxial Switch	MP59B	M70585	ANRITSU	N/A	N/A
Spectrum Analyzer	8595E	3441A00893	HP	2018.06.11	1Year
Amplifier	8447D	2727A05017	HP	2018.06.11	1Year
Bilog Antenna	VULB9163	9163/340	Schwarebeck	2018.06.11	1Year

#### 2.3 Harmonic & Flicker Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Harmonics Flicker Test System	PACS-1	72305	CI	2018.06.11	1Year
5K VA AC Power Source	5001iX	56060	CI	2018.06.11	N/A

#### 2.4 ESD Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
ESD Simulator	DITO	0404-24	EM TEST	2018.06.11	1Year

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## 2.5 RF field Strength Susceptibility

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Signal Generator	SMT03	100059	RS	2018.06.11	1Year
Power Meter	NRVS		RS	2018.06.11	1Year
Voltage Probe	URV5-Z2	100012	RS	2018.06.11	1Year
Voltage Probe	URV5-Z2	100013	RS	2018.06.11	1Year
Power Amplifier	150W1000	300999	AR	2018.06.11	1Year
Power Amplifier	25S1G4AM1	305993	AR	2018.06.11	1Year
Field Probe	CBL6111C	2576	Holaday	2018.06.11	1Year
Bilog Antenna	MCDC		Chase	2018.06.11	1Year

## Electrical Fast Transient/Burst (EFT/B) Immunity test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EFT Generator	UCS 500 M4	0304-42	EM TEST	2018.06.11	1Year
Power Source	MV2616	0104-14	EM TEST	2018.06.11	1Year

## 2.7 Surge Test

					Calibration
Name	Model No.	Serial No.	Manufacturer	Calibration Date	Cycle
Ultra Compact	UCS 500				
Simulator	M4	0304-42	EM TEST	2018.06.11	1Year
Power Source	MV2616	0104-14	EM TEST	2018.06.11	1Year

## 2.8 Conducted Immunity Test

					Calibration
Name	Model No.	Serial No.	Manufacturer	Calibration Date	Cycle
Continuous					
Wave Simulator	CWS 500C	0407-05	EM TEST	2018.06.11	1 Year

## Power-frequency Magnetic Field

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Continuous Wave					
Simulator	UCS 500 M4	0304-42	EM TEST	2018.06.11	1 Year
Power Source					
Network	MV 2616	0104-14	EM TEST	2018.06.11	1 Year
Current Transformer	MC2630		EM TEST	2018.06.11	1 Year

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Magnetic Coil	MS100	0304-42	EM TEST	2018.06.11	1 Year

## 2.10 Voltage Dips/Interruption Immunity Test

		,			
				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Ultra Compact					
Simulator	UCS 500 M4	0304-42	EM TEST	2018.06.11	1Year
Power Source	MV2616	0104-14	EM TEST	2018.06.11	1Year

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## 3.0 Technical Details

#### 3.1 Investigations Requested

Perform Electromagnetic Interference [EMI] & Electromagnetic Susceptibility[ EMS] tests for CE Marking

#### 3.2 Test Standards

	Test Standards							
EN 55032:2015	Electromagnetic compatibility of multi	Electromagnetic compatibility of multimedia equipment - Emission Requirements						
ENG1000 2 2.2014	Electromagnetic compatibility(EMC)-	Part 3-2:Limits-Limits for harmonic current						
EN61000-3-2:2014	emissions(equipment input current ≤	16A per phase)						
	Electromagnetic compatibility (EMC	C)- Part 3-3:Limits-Limitation of voltage						
EN 61000-3-3:2013	changes, Voltage fluctuations and flick	er in public low-voltage supply systems. For						
EN 01000-3-3.2013	equipment with rated current $\leq 16A$	per phase and not subject to conditional						
	connection	connection						
EN	Information technology equipment -	Information technology equipment — Immunity characteristics — Limits and						
55024:2010+A1:2015	methods of measurement							
	EN 61000-4-2:2009	Electrostatic discharge						
	EN 61000-4-3:2006	RF field strength susceptibility						
	EN 61000-4-4:2012	Electrical Fast transients						
	EN 61000-4-5:2014	Surge						
	EN 61000-4-6:2009	Conducted susceptibility						
	EN 61000-4-8:2010	Power-frequency Magnetic Field						
	EN 61000-4-11:2004	Dips/Voltage Interruption Variation						

#### 3.3 Performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

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## 3.4 Test standards and Results Summary Tables

Test Condition	Test Requirement	Test Method	Test Result						
	EMISSION Results Summary								
Conducted Emission on AC Mains,	EN 55032:2015	EN 55032:2015	Pass						
150kHz to 30MHz			1 455						
Conducted Emission on at	EN 55032:2015	EN 55032:2015							
telecommunication ports,			N/A						
150KHz to 30MHz									
Radiated Emissions,	EN 55032:2015	EN 55032:2015	Pass						
30MHz to 1GHz			F 488						
Harmonic Emissions on AC supply	EN61000-3-2:2014	EN61000-3-2:2014	N/A						
Voltage fluctuations on AC supply	EN 61000-3-3: 2013	EN 61000-3-3: 2013	N/A						
	IMMUNITY Results Sumi	mary							
Electrostatic Discharge	EN 55024: 2010+A1:2015	EN 61000-4-2: 2009	Pass						
Electrical Fast transients	EN 55024: 2010+A1:2015	EN 61000-4-4: 2012	Dogg						
/Burst Immunity			Pass						
RF field strength susceptibility	EN 55024: 2010+A1:2015	EN 61000-4-3: 2006	Pass						
Surge	EN 55024: 2010+A1:2015	EN 61000-4-5: 2014	Pass						
Conducted susceptibility	EN 55024: 2010+A1:2015	EN 61000-4-6: 2009	Pass						
Power-frequency Magnetic Field	EN 55024: 2010+A1:2015	EN61000-4-8: 2010	N/A						
Dips/Voltage Interruption Variation	EN 55024: 2010+A1:2015	EN 61000-4-11: 2004	Pass						

Note: N/A-Not applicable

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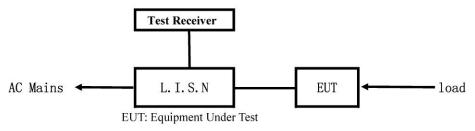


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## 4.0 Electromagnetic Interference Test results

#### 4.1 Power line Conducted Emission Test

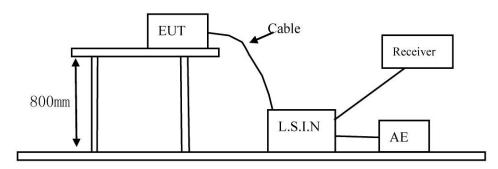
#### 4.1.1 Schematics of the test



#### 4.1.2 Test Method:

The test was performed in accordance with EN 55032:2015

## **Block diagram of Test setup**



## 4.1.3 Power line conducted Emission Limit

	Limits dB( µ V)								
Frequency(MHz)	Class A I	Equipment	Class B Equipment						
	Quasi-peak Level	Average Level	Quasi-peak Level	Average Level					
$0.15 \sim 0.50$	79.0	66.0	66.0~56.0*	56.0~46.0*					
$0.50 \sim 5.00$	73.0	60.0	56.0	46.0					
5.00 ~ 30.00	73.0	60.0	60.0	50.0					

Notes:

- 1. \*decreasing linearly with logarithm of frequency.
- 2. The lower limit shall apply at the transition frequencies

#### 4.1.4 Test Results

Limits for Conducted Emission test, Please refer to limit line (Quasi-peak)and Average in the following diagram labelled as (QP)&AV

#### Remark:

Calculated measurement uncertainty=3.6dB

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# A: Conducted Emission on Live Terminal (150kHz to 30MHz)

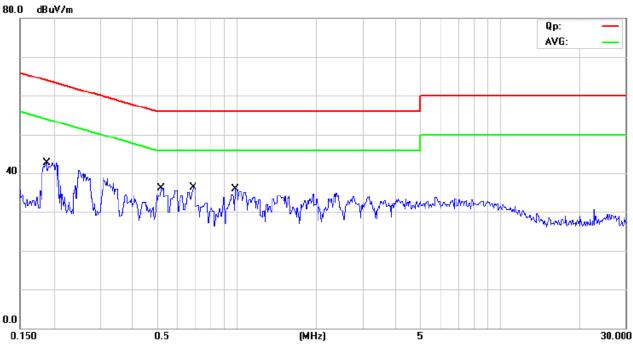
**EUT Operating Environment** 

Temperature: 26°C Humidity: 65%RH Atmospheric Pressure: 101 kPa

**EUT set Condition: Charging Equipment Level: Class B** 

**Results: Pass** 

Please refer to following diagram for individual



No. I	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
		MHz	dBuV/m	dB	dBuV/m	dBuV/m	dB	Detector	Comment
1		0.1887	28.60	9.89	38.49	64.09	-25.60	QP	
2		0.1887	11.40	9.89	21.29	54.09	-32.80	AVG	
3		0.5175	19.40	10.30	29.70	56.00	-26.30	QP	
4		0.5175	-6.10	10.30	4.20	46.00	-41.80	AVG	
5	*	0.6846	21.00	10.51	31.51	56.00	-24.49	QP	
6		0.6846	-1.90	10.51	8.61	46.00	-37.39	AVG	
7		0.6846	-2.00	10.51	8.51	46.00	-37.49	AVG	
8		0.9893	16.70	10.89	27.59	56.00	-28.41	QP	
9		0.9893	-6.50	10.89	4.39	46.00	-41.61	AVG	

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## B: Conducted Emission on Neutral Terminal (150kHz to 30MHz)

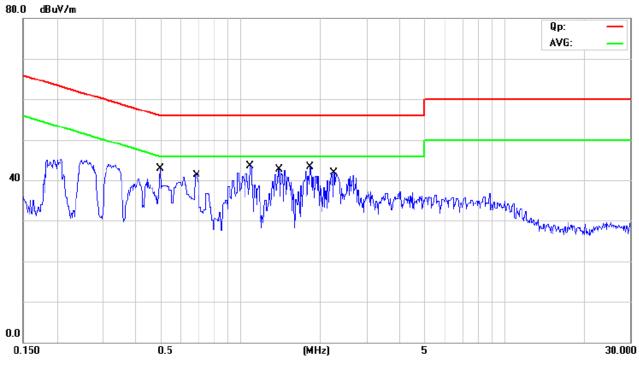
**EUT Operating Environment** 

Temperature: 26°C Humidity: 65%RH Atmospheric Pressure: 101 kPa

EUT set Condition: Charging Equipment Level: Class B

**Results: Pass** 

Please refer to following diagram for individual



			Reading	Correct	Measure-				
No.	Mk.	Freq.	Level	Factor	ment	Limit	Over		
		MHz	dBuV/m	dB	dBuV/m	dBuV/m	dB	Detector	Comment
1		0.4972	23.10	10.27	33.37	56.05	-22.68	QP	
2		0.4972	-6.90	10.27	3.37	46.05	-42.68	AVG	
3	*	0.6834	24.40	10.51	34.91	56.00	-21.09	QP	
4		0.6834	0.30	10.51	10.81	46.00	-35.19	AVG	
5		1.0914	21.70	10.90	32.60	56.00	-23.40	QP	
6		1.0914	-0.50	10.90	10.40	46.00	-35.60	AVG	
7		1.4013	20.80	10.89	31.69	56.00	-24.31	QP	
8		1.4013	-1.70	10.89	9.19	46.00	-36.81	AVG	
9		1.8300	19.60	10.88	30.48	56.00	-25.52	QP	
10		1.8300	0.90	10.88	11.78	46.00	-34.22	AVG	
11		2.2250	18.50	10.88	29.38	56.00	-26.62	QP	
12		2.2250	0.90	10.88	11.78	46.00	-34.22	AVG	

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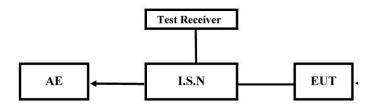
Date: 2018-09-19



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## 4.2 Telecommunication ports Conducted Emission Test

#### 4.2.1 Schematics of the test

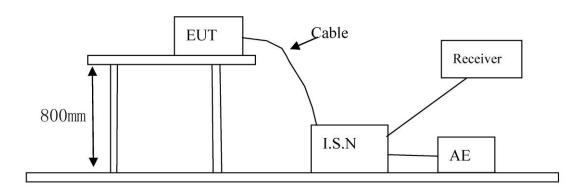


**EUT: Equipment Under Test** 

#### 4.2.2 Test Method:

The test was performed in accordance with EN 55032:2015

## **Block diagram of Test setup**



## 4.2.3 Telecommunication ports conducted Emission Limit

Frequency(MHz)		Class A	Limits		Class B Limits				
	Quasi-peak Level		Average Level		Quasi-peak Level		Average Level		
	Vlotage	Current	Vlotage	Current	Vlotage	Current	Vlotage	Current	
	dB(uV) dB(uA)		dB(uV) dB(uA)		dB(uV) dB(uA)		dB(uV) dB(uA)		
$0.15 \sim 0.50$	97 to 87	53 to43	84 to74	40 to 30	84 to 74	40 to30	74 to64	30 to 20	
0.50 ~ 30.00	87	43	74	30	74	30	64	20	

Notes:

- 1. \*decreasing linearly with logarithm of frequency.
- 2. The tighter limit shall apply at the transition frequencies

#### 4.2.4 Test Results

Limits for Conducted Emission test, Please refer to limit line (Quasi-peak)and Average in the following diagram labelled as (QP)&AV

## Remark:

Calculated measurement uncertainty=1.9dB

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## A: Conducted Emission on Telecommunication port (150kHz to 30MHz)

**EUT Operating Environment** 

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 kPa

**EUT set Condition: Normal operation mode** 

**Equipment Level: Class B** 

Results: N/A

Please refer to following diagram for individual

Frequency	Port	Reading(	dBμV)	Limit(	dBμV)
(MHz)	Port	Quasi-peak	Average	Quasi-peak	Average
	LAN				
	LAN				

Note: No such port, not applicable.

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## B: Conducted Emission on Telecommunication port (150kHz to 30MHz)

**EUT Operating Environment** 

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 kPa

**EUT set Condition: Normal operation mode** 

**Equipment Level: ClassB** 

Results: N/A

Please refer to following diagram for individual

Frequency	Dort	Reading(	dBμA)	Limit(	dBμA)
(MHz) Port		Quasi-peak	Average	Quasi-peak	Average
	LAN				

Note: No such port, not applicable.

Date: 2018-09-19

4.3



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# Radiated Disturbance Test

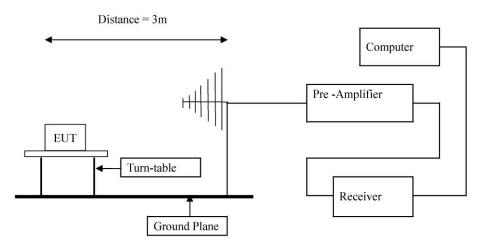
#### Schematics of the test



#### 4.3.2 Test Method:

The test was performed in accordance with EN 55032:2015

#### **Block diagram of Test setup**



#### 4.3.3 **Radiated Disturbance Test Limit**

Frequency Range (MHz)	Quasi-Peak limits (dB $\mu$ V/m)				
	Class A Limits	Class B Limits			
30-230	50.00	40.00			
230-1000	57.00	47.00			

Note: The lower limit shall apply at the transition frequencies

#### 4.3.4 Test result

Limits for Radiated Disturbance test, Please refer to limit line (Quasi-peak) in the following diagram labelled as (QP)

#### Remark:

Calculated measurement uncertainty=4.7dB

Date: 2018-09-19



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#### Radiated Disturbance (30MHz----1000MHz) A:

Project Number: CASE1 Test Time: 2018-09-18 17.33.34

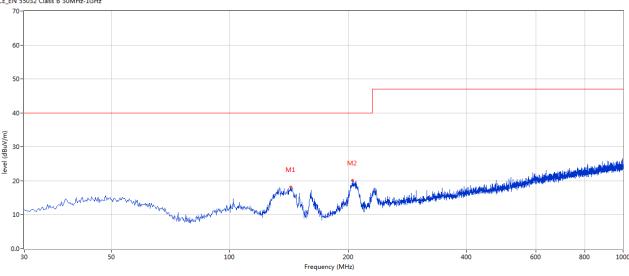
**EUT Name: CHARGING CABLE** Remark:

Manufacturer: N.A Model: MC18 Temp.(oC): 25 Hum.: 65%

Test Engineer: **CHARLES** Test Standard: EN 55032 Work Addition: **CAHRGING** 

Load:

CE\_EN 55032 Class B 30MHz-1GHz



No.	Frequen	Results	Factor	Limit	Over	Detector	Table (o)	Height	ANT	Verdict
	cy (MHz)	(dBuV/m	(dB)	(dBuV/m	Limit			(cm)		
		)		)	(dB)					
1	142.734	18.22	-17.30	40.0	-21.78	Peak	360.00	200	Н	Pass
2	205.284	20.17	-13.61	40.0	-19.83	Peak	360.00	200	Н	Pass

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## B: Radiated Disturbance (30MHz----1000MHz)

Project Number: CASE1 Test Time: 2018-09-18\_17.27.53

EUT Name: CHARGING CABLE Remark: Manufacturer: N.A Name:

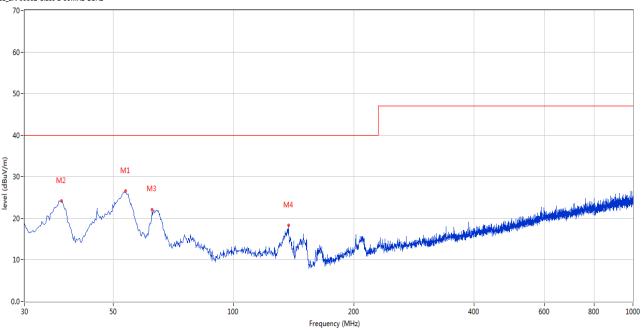
Model:MC18Project Template:Temp.(oC):25Manufacture:Hum.:65%Model Name:Test Engineer:CHARLESTempl.(oC):

Test Standard: EN 55032 Hum:

Work Addition: CHARGING Work Addition:

Load:

CE\_EN 55032 Class B 30MHz-1GHz



No.	Frequency	Results	Factor (dB)	Limit	Over Limit	Detector	Table	Height	ANT	Verdict
	(MHz)	(dBuV/m)		(dBuV/m)	(dB)		(o)	(cm)		
1	53.759	26.60	-11.53	40.0	-13.40	Peak	226.00	100	V	Pass
2	37.031	24.21	-13.17	40.0	-15.79	Peak	43.00	100	V	Pass
3	62.487	22.12	-13.28	40.0	-17.88	Peak	306.00	200	V	Pass
4	137.401	18.35	-17.23	40.0	-21.65	Peak	360.00	100	V	Pass

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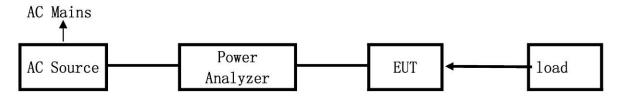
Date: 2018-09-19



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#### 4.4 Harmonic Current Emission Test

#### 4.4.1 Schematic of the test



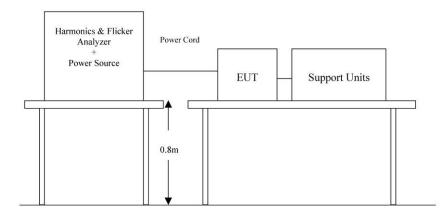
**EUT: Equipment Under Test** 

#### 4.4.2 Test Method:

The test was performed in accordance with EN61000-3-2:2014

\*: The Level of the product is: CLASS D

## **Block diagram of Test setup**



#### 4.4.3 Limits of Harmonic Current Emission For Class A

Harmonic order	Maximum permissible harmonic current
n	Α
Odd har	monics
3	2,30
5	1,14
7	0,77
9	0,40
11	0,33
13	0,21
15 ≤ n ≤ 39	0,15 1 <u>5</u>
Even har	monics
2	1,08
4	0,43
6	0,30
8 ≤ n ≤ 40	0,23 <u>8</u>

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#### 4.4.4 Test Results

Please refer to the following pages

**Harmonic Current Emission Test** 

**EUT Operating Environment** 

Temperature: 25°C Humidity: 53%RH Atmospheric Pressure: 101 Kpa

**EUT set Condition:** 

Results: N/A

Please refer to following diagram for individual

#### Harmonic results as a% of the limits

No	(Test	No	(Test	No	(Test	No	(Test
	result/Limit)%		result/Limit)%		result/Limit)%		result/Limit)%
1		11		21		31	
2		12		22		32	
3		13		23		33	
4		14		24		34	
5		15		25		35	
6		16		26		36	
7		17		27		37	
8		18		28		38	
9		19		29		39	
10		20		30		40	

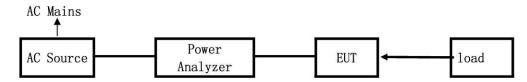
Date: 2018-09-19



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#### 4.5 Voltage Fluctuations & Flicker Test

#### 4.5.1 Schematic of the test

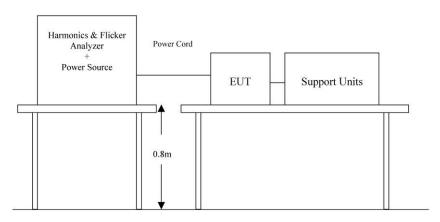


EUT: Equipment Under Test

#### 4.5.2 Test Method:

The test was performed in accordance with EN 61000-3-3:2013

## **Block diagram of Test setup**



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## 4.5.3 Test Results

Result: N/A

Please refer to following diagram for individual

## Maximum Occurring Levels:

Ut: 230.1 (EUT Test RMS Voltage)

Pst:	Limit=	1.0	(The Highest short Term Flicker Value)
Plt:	Limit=	0.65	(The Highest Long Term Flicker Value)
dt(%):	Limit=	3.3%	(The Highest instantaneous Voltage Change (10ms))
dc(%):	Limit=	3.3%	(The highest Relative steady state voltage change (1sec))
dmax:	Limit=	4%	(The highest Max Relative voltage change)
Tdt:	Limit=	500ms	(The Max Time(in milli-sec) that dt exceeds 3%)

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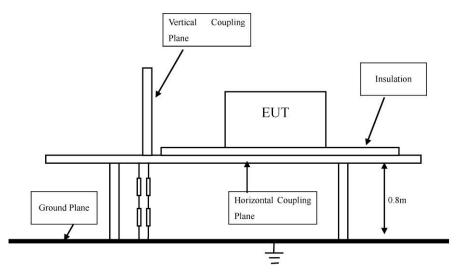


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## 5.0 Immunity Test

#### 5.1 Electrostatic Discharge

#### 5.1.1 Schematic of the test



#### 5.1.2 Test method

The test was performed in accordance with EN 61000-4-2: 2009

#### 5.1.3 Test severity

- ±4Kv for direct & in-direct Contact Discharge
- $\pm 8$ Kv for air Discharge

Performance Criterion Require: **B** (Please see following table)

## 5.1.4 Susceptibility performance Criteria and Severity level

Criterion	Description				
A No change in operational mode or degradation of performance outside specification and no change in stored parameters.					
B Degradation of performance allowed during the test the EUT returning intended operation after the test.					
C Loss of function allowed during the test, provided that function is sel recoverable or can be recovered by operation of controls.					

## Severity Level

Level	Test Voltage Direct & in-direct contact	Test Voltage Air
	Discharge (Kv)	discharge(Kv)
1	±2Kv	±2Kv
2	±4Kv	$\pm 4 \mathrm{Kv}$
3	±6Kv	±8Kv
4	±8Kv	±15Kv

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## 5.1.5 Test Result

#### **EUT Operating Environment**

Temperature: 25°C Humidity: 53%RH Atmospheric Pressure: 101 Kpa

Please refer to the following table for individual results.

Location	Discharge Method	Test Voltage	Results
НСР	In-Direct	$\pm 2kV, \pm 4kV$	Pass
VCP	In-Direct	$\pm 2kV, \pm 4kV$	Pass
Metal	Contact Discharge	$\pm 2kV, \pm 4kV$	Pass
Gap	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass
Enclosure	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass

**Remark:** Calculated measurement uncertainty= 0.2kV

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5.2



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# RF field strength susceptibility (80MHz----- 1000MHz)

#### 5.2.1 Schematics of the test



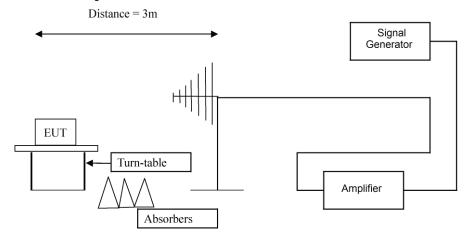
#### 5.2.2 Test Method:

The test was performed in accordance with EN 61000-4-3:2006

Level 2 (3V/m) Severity: 80% AM Modulation:

Performance Criterion Require: A (Please see following table)

## **Block diagram of Test setup**



#### 5.2.3 Susceptibility performance Criteria and severity Level

Susceptibility performance Criteria

Criterion	Description			
A No change in operational mode or degradation of performance out specification and no change in stored parameters.				
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.			
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.			

#### **Severity Level**

Level	Field Strength (V/m)
1	1
2	3
3	10

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## 5.2.4 Test Result:

## **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Frequency (MHz)	Face	Polarity	Level (V/m)	Dwell Time(s)	Sweep Rate (%)	Results
80-1000	0°	Horizontal	3	1	1	Pass
80-1000	90°	Horizontal	3	1	1	Pass
80-1000	180°	Horizontal	3	1	1	Pass
80-1000	270°	Horizontal	3	1	1	Pass
80-1000	0°	Vertical	3	1	1	Pass
80-1000	90°	Vertical	3	1	1	Pass
80-1000	180°	Vertical	3	1	1	Pass
80-1000	270°	Vertical	3	1	1	Pass

Remark: Calculated measurement uncertainty= 80MHz to 1000MHz (+3.7/-1.3) V/m

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## 5.3 Electrical Fast Transient/Burst (EFT/B) immunity test

#### 5.3.1 Schematics of the test



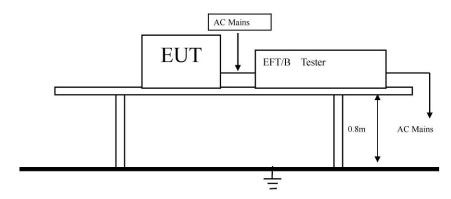
#### 5.3.2 Test Method

The test was performed in accordance with EN 61000-4-4:2012

Severity: Level 2 (1kV)

Performance Criterion Require: B (Please see following table)

## **Block diagram of Test setup**



#### 5.3.3 Susceptibility performance Criteria and Severity Level

Criterion	Description					
A No change in operational mode or degradation of performance outsi specification and no change in stored parameters.						
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.					
С	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.					

#### Severity Level

	Open Circuit output Test Voltag	e ±10%
Level	On power Supply Lines	On I/O (Input/output)
		Signal data and control lines
1	0.5kV	0.5kV
2	1kV	1kV
3	2kV	2kV
4	4kV	4kV
X	Special	Special

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## 5.3.4 Test Results

## **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to following page.

Inject location: AC mains

Inject Line	Voltage kV	Inject Times (s)	Method	Results
L	±1	120	Direct	Pass
N	±1	120	Direct	Pass
L-N	±1	120	Direct	Pass

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## 5.4 Surge test

#### 5.4.1 Schematics of the test



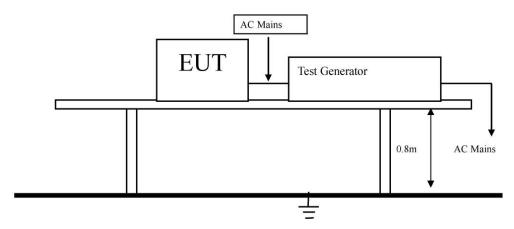
#### **5.4.2** Test Method:

The test was performed in accordance with EN 61000-4-5:2014

Severity: Level 2 (Line to Neutral at 1kV)

Performance Criterion Require: B (Please see following table)

## **Block diagram of Test setup**



#### 5.4.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A No change in operational mode or degradation of performance outsic specification and no change in stored parameters.	
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

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#### Severity Level

Severity Level	Open-Circuit Test Voltage		
	kV		
1	0.5		
2	1.0		
3	2.0		
4	4.0		
*	Special		

#### 5.4.4 Test Results

## **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to following page.

Test location:

Location	Polarity	Phase	No of	Pulse	Results
		Angle	Pulse	Voltage(kV)	
	±	0	5	1.0	Pass
LN	<u>±</u>	90	5	1.0	Pass
L-N	<u>±</u>	180	5	1.0	Pass
	±	270	5	1.0	Pass

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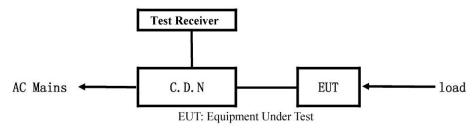


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# Jaic. 2010-09-19

## 5.5 Conducted Immunity test

#### 5.5.1 Schematics of the test



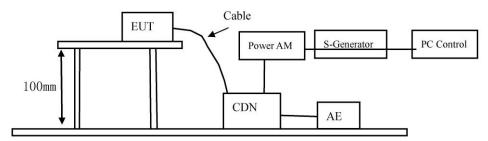
#### 5.5.2 Test Method

The test was performed in accordance with EN 61000-4-6:2009

Severity: Level 2 (3 V rms),0.15MHz—80MHz

Performance Criterion Require: A (Please see following table)

## **Block diagram of Test setup**



#### 5.5.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A No change in operational mode or degradation of performance outside of specification and no change in stored parameters.	
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

## Severity Level

Severity Level	Voltage Level (e.m.f) V
1	1
2	3
3	10
*	Special

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## 5.5.4 Test Results:

#### **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following page

Frequency Range (MHz)	Injected Position	Strength	Criterion	Observation	Result
0.15 - 20	AC Line	3V (rms) Unmodulated	A	A	Pass
20 - 80	AC Line	3V (rms) Unmodulated	A	A	Pass

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## 5.6 Power-Frequency magnetic field test

#### 5.6.1 Schematics of the test



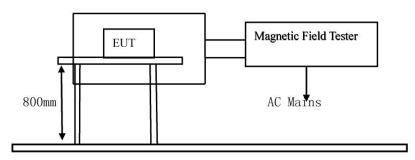
#### 5.6.2 Test Method

The test was performed in accordance with EN 61000-4-8:2010

Severity: Level 1 (1A/m),

Performance Criterion Require: A (Please see following table)

## **Block diagram of Test setup**



## 5.6.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description	
A No change in operational mode or degradation of performance outside of specification and no change in stored parameters.		
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.	
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.	

#### Severity Level

Severity Level	Magnetic Field Strength A/m
1	1
2	3
3	10
4	30
5	100
*	Special

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## 5.6.4 Test Results:

## **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following page

Test Level	Testing Duration	Coil Orientation	Criterion	Result		
1A/m	5 Mins	X	A	N/A		
1A/m	5 Mins	Y	A	N/A		
1A/m	5 Mins	Z	A	N/A		

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## 5.7 Voltage Dips/Interruptions immunity test

#### 5.7.1 Schematics of the test

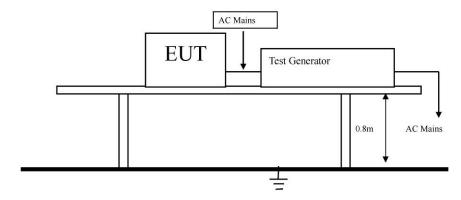


#### 5.7.2 Test Method:

The test was performed in accordance with EN 61000-4-11:2004

Performance Criterion Require: C&B (Please see following table)

## **Block diagram of Test setup**



#### 5.7.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Criterion Description	
A No change in operational mode or degradation of performance outside of specification and no change in stored parameters.		
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.	
C Loss of function allowed during the test, provided that function i recoverable or can be recovered by operation of controls.		

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## Severity Level

	Test Level %Ut	Reduction	Duration	Performance
Voltage			(Periods)	Criteria
Dip	<5	>95	0.5	В
	70	30	25	С
V-14	Test Level %Ut	Reduction	Duration	Performance
Voltage			(Periods)	Criteria
Interceptions	<5	>95	250	C

#### 5.7.4 Test Result:

## **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following page

Voltage Dip:

Test Level	Reduction	Duration	Phase Angle	Meet	Result
% Ut		(periods)		Criterion	
0	100	0.5	0° -360°	A	Pass
70	30	25	0° - 360°	A	Pass

## Voltage Interceptions:

,	Test Level % Ut	Reduction	Duration (periods)	Phase Angle	Meet Criterion	Result
	0	100	250	0° - 360°	В	Pass

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## **6.0 Product Labelling**

## 6.1 CE Mark label specification

Text of the mark is black or white in color and is left justified. Labels are printed in indelible ink on permanent adhesive backing and shall be affixed at a conspicuous location on the EUT or silk-screened onto the EUT.



6.2 Mark Location: Rear enclosure

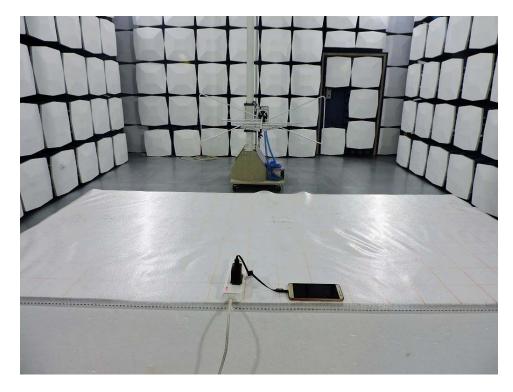
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## 7.0 Photo of testing





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## Photo for the EUT





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30 40 50 60



90 00 110 120 130 140 150 160

-End of the report-

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